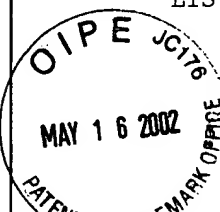


FORM PTO-1449	Atty. Docket No.: R11.12-0749	Appl. No.: 09/852,102
 <p>LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT</p>	First Named Inventor:	
	Evren Eryurek et al.	
	Filing Date	Group Art:
	May 9, 2001	2857


## U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Date	Name	Class	Sub Class	Filing Date If Appropriate
JRW	AA	3,618,592	11/9/71	Stewart et al.	<del>600 128</del>	<del>484 2.05</del>
JRW	AB	4,668,473	5/26/87	Agarwal	422	62
JRW	AC	4,720,806	1/19/88	Schippers et al.	<del>702 364</del>	<del>187 551</del>
JRW	AD	4,736,763	4/12/88	Britton et al.	137	10
JRW	AE	5,089,979	2/18/92	McEachern et al.	<del>702 364</del>	<del>715 21.04</del>
JRW	AF	5,365,787	11/22/94	Hernandez et al.	73	660
JRW	AG	5,436,705	7/25/95	Raj	<del>399 355</del>	<del>59 246</del>
JRW	AH	5,526,293	6/11/96	Mozumder et al.	<del>716 364</del>	<del>19 578</del>
JRW	AI	5,539,638	7/23/96	Keeler et al.	<del>701 364</del>	<del>29 424.03</del>
JRW	AJ	5,591,922	1/7/97	Segeral et al.	73	861.04
JRW	AK	5,633,809	5/27/97	Wissenbach et al.	<del>702 364</del>	<del>45 510</del>
JRW	AL	5,708,211	1/13/98	Jepson et al.	73	861.04
JRW	AM	5,710,370	1/20/98	Shanahan et al.	73	1.35
JRW	AN	5,736,649	4/7/98	Kawasaki et al.	73	861.23
JRW	AO	5,747,701	5/5/98	Marsh et al.	73	861.23
JRW	AP	5,817,950	10/6/98	Wiklund et al.	73	861.66
JRW	AQ	5,908,990	6/1/99	Cummings	73	861.22
JRW	AR	6,072,150	6/6/00	Sheffer	219	121.83
JRW	AS	6,112,131	8/29/00	Ghorashi et al.	700	142
JRW	AT	6,119,529	9/19/00	DiMarco et al.	73	861.68
JRW	AU	6,236,948	5/22/01	Eck et al.	702	45
JRW	AV	6,311,136	10/30/01	Henry et al.	702	45
JRW	AW	6,327,914	12/11/01	Dutton	73	861.356

EXAMINER:

DATE CONSIDERED:

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449	Atty. Docket No.: R11.12-0749	Appl. No.: 09/852,102
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## FOREIGN PATENT DOCUMENTS

		Document No.	Date	Country	Class	Sub Class	Translation Yes No
JRW	AN	03229124	11/10/91	Japan			X (abstract only)
JRW	AO	0 512 794 A2	5/5/92	EPO			X

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

JRW	AP	Journal of Intelligent Manufacturing (1997) 8, 271-276 article entitled "On-line tool condition monitoring system with wavelet fuzzy neural network"
	AQ	
EXAMINER: <i>[Signature]</i>		
DATE CONSIDERED: 12/07/02		

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.